

**Search Notes**

Application/Control No.

10/711,224

Examiner

Mohamed Charioui

Applicant(s)/Patent under  
Reexamination

HYDE ET AL.

Art Unit

2857

**SEARCHED**

Class	Subclass	Date	Examiner
702	57, 60, 65, 93, 99, 116, 119	5/22/2006	MC
702	130, 136	5/22/2006	MC
702	170, 182	5/22/2006	MC
702	183, 189	5/22/2006	MC
702	193	5/22/2006	MC
257	59, 347	5/22/2006	MC
257	401, 577	5/22/2006	MC
257	706	5/22/2006	MC
438	163	5/22/2006	MC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East: "silicon island" and (transistor\$1 with temperature) and (transistor\$1 with (distance or width))	5/22/2006	MC
East: "silicon island" and (transistor\$1 with temperature) and (temperature near measur\$6)	5/22/2006	MC
"silicon island" and (transistor\$1 with temperature) and (temperature near measur\$6) and diatnce	5/22/2006	MC
IEEE: search by inventor's name	5/22/2006	MC